



Final Product/Process Change Notification

Document #:FPCN24561XH

Issue Date:02 Jan 2024

Title of Change:	Qualification of Q-FET discrete products at onsemi Roznov, Czech Republic.									
Proposed First Ship date:	09 Apr 2024 or earlier if approved by customer									
Contact Information:	Contact your local onsemi Sales Office or Gapyeol.Kim@onsemi.com									
PCN Samples Contact:	Contact your local onsemi Sales Office. Sample requests are to be submitted no later than 30 days from the date of first notification, Initial PCN or Final PCN, for this change. Samples delivery timing will be subject to request date, sample quantity and special customer packing/label requirements.									
Additional Reliability Data:	Contact your local onsemi Sales Office or songyong.sim@onsemi.com									
Type of Notification:	This is a Final Product/Process Change Notification (FPCN) sent to customers. FPCNs are issued 90 days prior to implementation of the change. onsemi will consider this change accepted, unless an inquiry is made in writing within 30 days of delivery of this notice. To do so, contact PCN.Support@onsemi.com									
Marking of Parts/ Traceability of Change:	Date Code									
Change Category:	Wafer Fab Change									
Change Sub-Category(s):	Manufacturing Site Transfer									
Sites Affected:										
onsemi Sites	External Foundry/Subcon Sites									
onsemi Roznov, Czech Republic	None									
onsemi, ISMF Malaysia										
Description and Purpose:										
This notification is to inform the customers that onsemi qualified their Q-FET discrete products at onsemi Roznov, Czech Republic. Some of the parts may also undergo a wafer probe alternate location, but there is no impact to the 100% final electrical test.										
	<table><tr><th></th><th>From</th><th>To</th></tr><tr><td>Wafer Fab Site</td><td>onsemi Bucheon, Korea</td><td>onsemi Roznov, Czech Republic</td></tr><tr><td>Wafer Back Grinding and Back metal Site</td><td>onsemi Bucheon, Korea</td><td>onsemi ISMF, Malaysia</td></tr></table>		From	To	Wafer Fab Site	onsemi Bucheon, Korea	onsemi Roznov, Czech Republic	Wafer Back Grinding and Back metal Site	onsemi Bucheon, Korea	onsemi ISMF, Malaysia
	From	To								
Wafer Fab Site	onsemi Bucheon, Korea	onsemi Roznov, Czech Republic								
Wafer Back Grinding and Back metal Site	onsemi Bucheon, Korea	onsemi ISMF, Malaysia								
There are no product material changes and no product marking changes.										



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Reliability Data Summary:

QV DEVICE NAME: FQD18N20V2TM

RMS: U90867

PACKAGE: DPAK

Test	Specification	Condition	Interval	Results
HTRB	JESD22-A108	Tj= 150°C, 80% max rated V	1008 hrs	0/231
HTGB	JESD22-A108	Tj= 150°C, 100% max rated Vgss	1008 hrs	0/240
HTSL	JESD22-A103	Ta= 150°C	1008 hrs	0/240
PC	J-STD-020 JESD-A113	MSL 1 @ 260°C, Pre TC, uHAST, HAST for surface mount pkgs only	-	-
TC	JESD22-A104	Ta= -55°C to +150°C	1000 cyc	0/231
HAST	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs	0/240
uHAST	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs	0/240

QV DEVICE NAME: FQA28N50

RMS: K84460

PACKAGE: TO3P

Test	Specification	Condition	Interval	Results
HTRB	JESD22-A108	Tj= 150°C, 80% max rated V	1008 hrs	0/80
HTGB	JESD22-A108	Tj= 150°C, 100% max rated Vgss	1008 hrs	0/80
HTSL	JESD22-A103	Ta= 150°C	1008 hrs	0/80
TC	JESD22-A104	Ta= -55°C to +150°C	1000 cyc	0/40
HAST	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs	0/40
uHAST	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs	0/40
HTRB	JESD22-A108	Tj= 150°C, 80% max rated V	1008 hrs	0/80

QV DEVICE NAME: FQA70N15

RMS: K87030

PACKAGE: TO3P

Test	Specification	Condition	Interval	Results
HTRB	JESD22-A108	Tj= 175°C, 80% max rated V	1008 hrs	0/80
HTGB	JESD22-A108	Tj= 175°C, 100% max rated Vgss	1008 hrs	0/80
HTSL	JESD22-A103	Ta= 175°C	1008 hrs	0/80
TC	JESD22-A104	Ta= -55°C to +150°C	1000 cyc	0/40
HAST	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs	0/40
uHAST	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs	0/40
HTRB	JESD22-A108	Tj= 175°C, 80% max rated V	1008 hrs	0/80



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QV DEVICE NAME: FQD2N100TM

RMS: K87031

PACKAGE: DPAK

Test	Specification	Condition	Interval	Results
HTRB	JESD22-A108	Tj= 150°C, 80% max rated V	1008 hrs	0/80
HTGB	JESD22-A108	Tj= 150°C, 100% max rated Vgss	1008 hrs	0/80
HTSL	JESD22-A103	Ta= 150°C	1008 hrs	0/80
PC	J-STD-020 / JESD-A113	MSL 1 @ 260°C, Pre TC, uHAST, HAST for surface mount pkgs only	-	-
TC	JESD22-A104	Ta= -55°C to +150°C	1000 cyc	0/40
HAST	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs	0/39
uHAST	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs	0/39

Electrical Characteristics Summary:

Electrical characteristics are not impacted.

List of Affected Parts:

Note: Only the standard (off the shelf) part numbers are listed in the parts list. Any custom parts affected by this PCN are shown in the customer specific PCN addendum in the PCN email notification, or on the [PCN Customized Portal](#).

Part Number	Qualification Vehicle
FQP27P06	FQA28N50, FQA70N15, FQD2N100TM, FQD18N20V2TM
FQPF7P20	FQA28N50, FQA70N15, FQD2N100TM, FQD18N20V2TM
FQD2P40TM	FQA28N50, FQA70N15, FQD2N100TM, FQD18N20V2TM
FQD11P06TM	FQA28N50, FQA70N15, FQD2N100TM, FQD18N20V2TM
FQB22P10TM	FQA28N50, FQA70N15, FQD2N100TM, FQD18N20V2TM
FQB12P20TM	FQA28N50, FQA70N15, FQD2N100TM, FQD18N20V2TM
FQT5P10TF	FQA28N50, FQA70N15, FQD2N100TM, FQD18N20V2TM
FQP17P06	FQA28N50, FQA70N15, FQD2N100TM, FQD18N20V2TM
FDMC2523P	FQA28N50, FQA70N15, FQD2N100TM, FQD18N20V2TM
FQD8P10TM	FQA28N50, FQA70N15, FQD2N100TM, FQD18N20V2TM
PCFQ4P40W	FQA28N50, FQA70N15, FQD2N100TM, FQD18N20V2TM
FQPF47P06	FQA28N50, FQA70N15, FQD2N100TM, FQD18N20V2TM
FQP47P06	FQA28N50, FQA70N15, FQD2N100TM, FQD18N20V2TM
FQB34P10TM	FQA28N50, FQA70N15, FQD2N100TM, FQD18N20V2TM
FQPF27P06	FQA28N50, FQA70N15, FQD2N100TM, FQD18N20V2TM



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FQD18N20V2TM	FQA28N50, FQA70N15, FQD2N100TM, FQD18N20V2TM
FQD5P20TM	FQA28N50, FQA70N15, FQD2N100TM, FQD18N20V2TM
FQD17P06TM	FQA28N50, FQA70N15, FQD2N100TM, FQD18N20V2TM